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- Independent Registers for A and B Buses
- Multiplexed Real-Time and Stored Data
- Choice of True or Inverting Data Paths
- Choice of 3-State or Open-Collector Outputs
- Package Options Include Plastic Small-Outline (DW) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (NT) and Ceramic (JT) 300-mil DIPs

DEVICE	OUTPUT	LOGIC
SN54ALS646, SN74ALS646A, AS646	3 state	True
SN54ALS648, SN74ALS648A, SN74AS648	3 state	Inverting

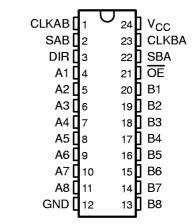
description

These devices consist of bus-transceiver circuits with 3-state or open-collector outputs, D-type flip-flops, and control circuitry arranged for multiplexed transmission of data directly from the data bus or from the internal storage registers. Data on the A or B bus is clocked into the registers on the low-to-high transition of the appropriate clock (CLKAB or CLKBA) input. Figure 1 illustrates the four fundamental bus-management functions that can be performed with the octal bus transceivers and registers.

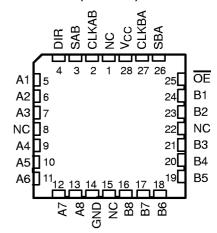
Output-enable (\overline{OE}) and direction-control (DIR) inputs control the transceiver functions. In the transceiver mode, data present at the high-impedance port may be stored in either or both registers.

The select-control (SAB and SBA) inputs can multiplex stored and real-time (transparent mode)

SN54ALS646, SN54ALS648, SN54AS646... JT PACKAGE SN74ALS646A, SN74ALS648A, SN74AS646, SN74AS648... DW OR NT PACKAGE (TOP VIEW)



SN54ALS646, SN54ALS648, SN54AS646 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

data. The circuitry used for select control eliminates the typical decoding glitch that occurs in a multiplexer during the transition between stored and real-time data. DIR determines which bus receives data when \overline{OE} is low. In the isolation mode (\overline{OE} high), A data may be stored in one register and/or B data may be stored in the other register.

When an output function is disabled, the input function is still enabled and can be used to store and transmit data. Only one of the two buses, A or B, may be driven at a time.

The -1 version of the SN74ALS646A is identical to the standard version, except that the recommended maximum I_{OL} in the -1 version is increased to 48 mA. There are no -1 versions of the SN54ALS646, SN54ALS648, or SN74ALS648A.

The SN54ALS646, SN54ALS648, and SN54AS646 are characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ALS646A, SN74ALS648A, SN74AS646, and SN74AS648 are characterized for operation from 0°C to 70°C.



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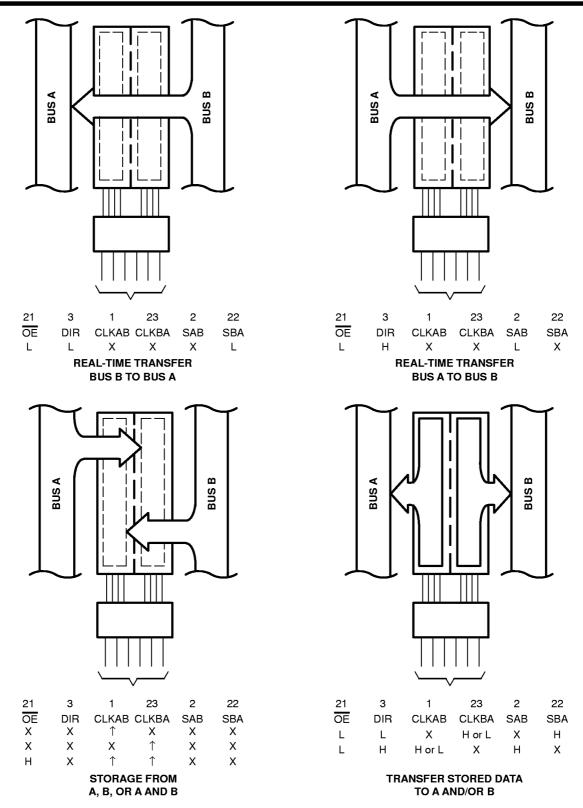


Figure 1. Bus-Management Functions

Pin numbers shown are for the DW, JT, and NT packages.



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Function Tables

SN54ALS646, SN54AS646, SN74ALS646A, SN74AS646

		INP	UTS			DAT	A I/O	OPERATION OR FUNCTION
ŌĒ	DIR	CLKAB	CLKBA	SAB	SBA	A1-A8	B1-B8	OPERATION OR FUNCTION
Х	Х	1	Х	Х	Х	Input	Unspecified [†]	Store A, B unspecified [†]
X	Χ	Χ	\uparrow	Χ	Χ	Unspecified [†]	Input	Store B, A unspecified [†]
Н	Х	1	↑	Х	Х	Input	Input	Store A and B data
Н	Χ	H or L	H or L	Χ	Χ	Input disabled	Input disabled	Isolation, hold storage
L	L	Х	Х	Х	L	Output	Input	Real-time B data to A bus
L	L	Χ	H or L	Χ	Н	Output	Input	Stored B data to A bus
L	Н	Х	Х	Ĺ	Х	Input	Output	Real-time A data to B bus
L	Н	H or L	Χ	Н	Χ	Input	Output	Stored A data to B bus

[†] The data output functions can be enabled or disabled by various signals at $\overline{\text{OE}}$ and DIR. Data input functions are always enabled; i.e., data at the bus terminals is stored on every low-to-high transition of the clock inputs.

SN54ALS648, SN74ALS648A, SN74AS648

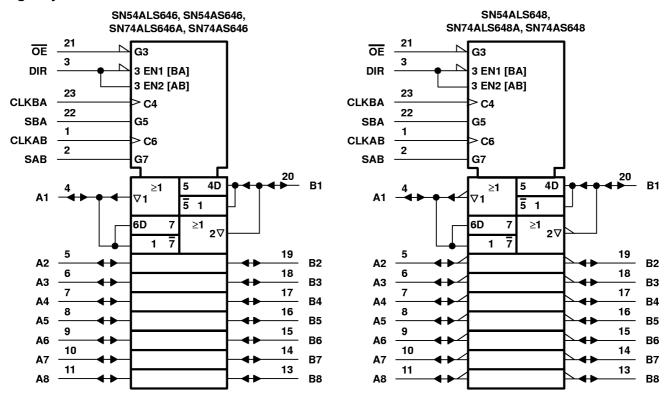
		INP	UTS			DATA I/O		OPERATION OR FUNCTION
ŌĒ	DIR	CLKAB	CLKBA	SAB	SBA	A1-A8	B1-B8	OPERATION OR FUNCTION
Х	Х	1	Х	Х	Х	Input	Unspecified [†]	Store A, B unspecified [†]
Х	Χ	Χ	1	Χ	Χ	Unspecified [†]	Input	Store B, A unspecified [†]
Н	Х	1	1	Х	Х	Input	Input	Store A and B data
Н	Χ	H or L	H or L	Χ	Χ	Input disabled	Input disabled	Isolation, hold storage
L	L	Х	Х	Х	L	Output	Input	Real-time B data to A bus
L	L	Х	H or L	Χ	Н	Output	Input	Stored B data to A bus
L	Н	Х	Х	Ĺ	Х	Input	Output	Real-time A data to B bus
L	Н	H or L	X	Н	Χ	Input	Output	Stored A data to B bus

[†] The data output functions can be enabled or disabled by various signals at OE and DIR. Data input functions are always enabled; i.e., data at the bus terminals is stored on every low-to-high transition of the clock inputs.



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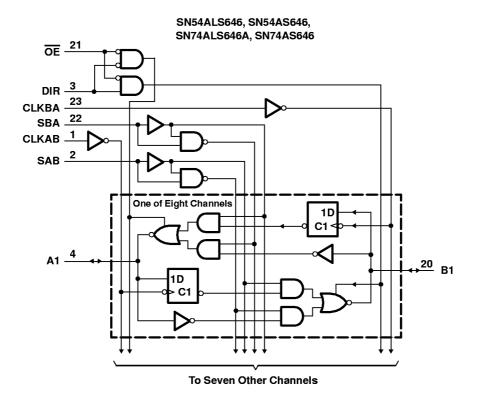
logic symbols†

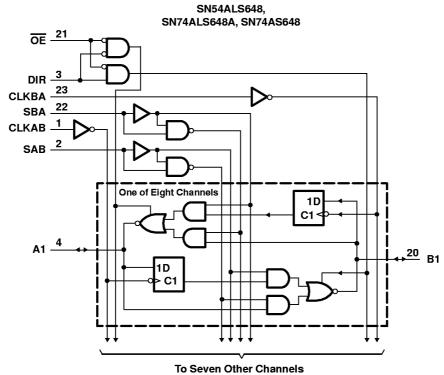


[†]These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the DW, JT, and NT packages.



logic diagrams (positive logic)





Pin numbers shown are for the DW, JT, and NT packages.



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}	$\dots \dots $
Input voltage, V _I : Control inputs	7 V
I/O ports	5.5 V
Operating free-air temperature range, T _A : SN54ALS646	55°C to 125°C
SN74ALS646A	0°C to 70°C
Storage temperature range	65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SI	SN54ALS646 SN74ALS646			6A	UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX	UNII
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage				2			V
V_{IL}	Low-level input voltage			0.7			8.0	V
IOH	High-level output current			-12			-15	mA
1	Low-level output current			12			24	mA
lOL							48‡	
fclock	Clock frequency	0		35	0		40	MHz
t _w	Pulse duration, CLKBA or CLKAB high or low	14.5			12.5			ns
t _{su}	Setup time, A before CLKAB↑ or B before CLKBA↑	15			10			ns
th	Hold time, A after CLKAB↑ or B after CLKBA↑	0			0			ns
TA	Operating free-air temperature	-55		125	0		70	°C

[‡] Applies only to the -1 version and only if V_{CC} is maintained between 4.75 V and 5.25



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	DADAMETED	TEGT 00	TEST CONDITIONS		54ALS6	46	SN7	4ALS64	6A	LINUT
	PARAMETER	TEST CO	INDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	UNIT
٧ _{IK}		V _{CC} = 4.5 V,	I _I = -18 mA			-1.2			-1.2	٧
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -0.4 \text{ mA}$	V _{CC} -2			V _{CC} -2			
Vau		V _{CC} = 4.5 V	$I_{OH} = -3 \text{ mA}$	2.4	3.2		2.4	3.2		V
VOH			$I_{OH} = -12 \text{ mA}$	2						V
			$I_{OH} = -15 \text{ mA}$				2			
			I _{OL} = 12 mA		0.25	0.4		0.25	0.4	
v_{OL}		V _{CC} = 4.5 V	I _{OL} = 24 mA					0.35	0.5	V
			$I_{OL} = 48 \text{ mA}^{\ddagger}$					0.35	0.5	
ı.	Control inputs	V 55V	V _I = 7 V			0.1			0.1	mA
=	A or B ports	V _{CC} = 5.5 V	$V_{ } = 5.5 \text{ V}$			0.1			0.1	IIIA
	Control inputs	, F.F.V.	\/ (1777 \)			20			20	μΑ
ΊΗ	A or B ports§	$V_{CC} = 5.5 V$	V _I = 2.7 V	20				2		
	Control inputs	.,				-0.2			-0.2	_
۱۱۲	A or B ports§	V _{CC} = 5.5 V,	V _I = '0'.4' V			-0.2			-0.2	mA
IO¶	_	V _{CC} = 5.5 V,	V _O = 2.25 V	-20		-112	-30		-112	mA
			Outputs high		47	76		47	76	mA
ICC		V _{CC} = 5.5 V	Outputs low		55	88		55	88	
			Outputs disabled		55	88		55	88	

 $^{^{\}dagger}$ All typical values are at $V_{CC} = 5 \text{ V}$, $T_{A} = 25^{\circ}\text{C}$.



[‡] Applies only to the -1 version and only if V_{CC} is maintained between 4.75 V and 5.25

[§] For I/O ports, the parameters I_{IH} and I_{IL} include the off-state output current.

The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

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PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _C C _L R1 R2 T _A	UNIT			
			SN54ALS646 SN74ALS646A		S646A]	
			MIN	MAX	MIN	MAX	
f _{max}			35		40		MHz
^t PLH	CLKBA or CLKAB	A or B	10	35	7	30	ns
^t PHL	CENDA OF CENAD	AOID	5	20	5	17	115
^t PLH	A or B	B or A	5	22	3	20	ns
[†] PHL		DOIA	3	15	3	12	115
^t PLH	SBA or SAB‡	I AOTH	10	40	7	35	ns
^t PHL	(stored data low)		5	23	5	20	
t _{PLH}	SBA or SAB‡	A or B	8	30	6	25	ns
^t PHL	(stored data high)	A or B	5	24	5	20	ns
^t PZH	le le	A or B	3	20	2	17	ns
t _{PZL}	Ö	AOIB	5	22	4	20	115
^t PHZ	Œ	A or B	1	12	1	10	ns
[†] PLZ	OE	7.01.0	1	20	2	16	1115
^t PZH	DIR	A or B	5	38	3	30	ns
[†] PZL	DIK	7010	5	30	4	25	""
[†] PHZ	DIR	R A or B	1	12	1	10	ns
t _{PLZ}	חות	AUID	2	21	2	16	115

T For conditions shown MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡]These parameters are measured with the internal output state of the storage register opposite that of the bus input.

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}	7 V
Input voltage, V _I : Control inputs	7 V
I/O ports	
Operating free-air temperature range, T _A : SN54ALS648	-55°C to 125°C
SN74ALS648A	0°C to 70°C
Storage temperature range	-65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		S	SN54ALS648			SN74ALS648A		
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
v_{IH}	High-level input voltage	2			2			٧
V_{IL}	Low-level input voltage			0.7			0.8	٧
loн	High-level output current			-12			-15	mA
loL	Low-level output current			12			24	mA
f _{clock}	Clock frequency	0		35	0		40	MHz
t _w	Pulse duration, CLKBA or CLKAB high or low	14.5			12.5			ns
t _{su}	Setup time, A before CLKAB↑ or B before CLKBA↑	15			10			ns
th	Hold time, A after CLKAB↑ or B after CLKBA↑	0			0			ns
TA	Operating free-air temperature	-55	-55 12 5		0		70	°C



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	DADAMETED	TEST OF	TEST CONDITIONS		54ALS6	48	SN7	'4ALS64	A8	UNIT
	PARAMETER	lesi cc			TYP	MAX	MIN	TYPT	MAX	UNII
V _{IK}		V _{CC} = 4.5 V,	l _l = −18 mA			-1.2			-1.2	٧
		V _{CC} = 4.5 V to 5.5 V,	$I_{OH} = -0.4 \text{ mA}$	V _{CC} -2			V _{CC} -2	1		
Vau			I _{OH} = −3 mA	2.4	3.2		2.4	3.2		٧
VOH		V _{CC} = 4.5 V	$I_{OH} = -12 \text{ mA}$	2						V
			$I_{OH} = -15 \text{ mA}$				2			
V - :		V _{CC} = 4.5 V	I _{OL} = 12 mA		0.25	0.4		0.25	0.4	V
VOL		VCC = 4.5 V	$I_{OL} = 24 \text{ mA}$					0.35	0.5	V
lı.	Control inputs	V00 - 5 5 V	V _I = 7 V			0.1			0.1	mA
Ц	A or B ports	V _{CC} = 5.5 V	V _I = 5.5 V			0.1			0.1	ША
1	Control inputs	trol inputs	\/. 37 7*\/			20			20	^
ļΗ	A or B ports‡	V _{CC} = 5.5 V,	V _I = 27.7 V			20			20	μΑ
	Control inputs	V 55V	V			-0.2			-0.2	^
IIL	A or B ports‡	$V_{CC} = 5.5 \text{ V},$	V _I = '0'.4' V			-0.2			-0.2	mA
ΙΟ§		$V_{CC} = 5.5 V$,	V _O = 2.25 V	-20		-112	-30		-112	mA
			Outputs high		47	76		47	76	mA
Icc		$V_{CC} = 5.5 \text{ V}$	Outputs low		57	88		57	88	
			Outputs disabled		57	88		57	88	

[†] All typical values are at V_{CC} = 5 V, T_A = 25°C.

[‡] For I/O ports, the parameters I_{IH} and I_{IL} include the off-state output current.

[§] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

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PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _C C _L R1 R2 T _A	UNIT			
			SN54ALS648 SN74ALS648A		S648A		
			MIN	MAX	MIN	MAX	
fmax			35		40		MHz
[†] PLH	CLKBA or CLKAB	A or B	8	39	7	33	ns
^t PHL	OLKBA OF OLKAD	AOID	5	23	5	20	10
^t PLH	A or B	B or A	3	20	2	17	ns
[†] PHL		DOIA	2	12	2	10	115
[†] PLH	SBA or SAB‡	A or B	5	44	5	39	ns
[†] PHL	(stored data low)	low)	4	26	4	22	113
^t PLH	SBA or SAB‡	A or B	6	30	6	25	ns
^t PHL	(stored data high)	Aorb	6	25	6	21	lis
^t PZH	Œ	A or B	4	25	2	22	ns
^t PZL	OE	AOID	4	25	4	22	115
^t PHZ	Œ	A or B	1	12	1	10	ns
^t PLZ	OE .	7010	2	21	2	15	113
^t PZH	DIR	A or B	4	35	2	27	ns
t _{PZL}	DIK	7010	3	25	3	19	113
^t PHZ	DIR	DIR A or B	1	17	1	14	ns
[†] PLZ	Dill	7010	2	22	2	15	113

T For conditions shown MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡] These parameters are measured with the internal output state of the storage register opposite that of the bus input.

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}	7'	٧
Input voltage, V _I : Control inputs	7	٧
I/O ports		
Operating free-air temperature range, T _A : SN54AS646	5°C to 125°0	С
SN74AS646	0°C to 70°0	С
Storage temperature range	5°C to 150°0	C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

			18	154AS64	16	18	174AS64	6	UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage		4.5	5	5.5	4.5	5	5.5	٧
V_{IH}	High-level input voltage		2			2			٧
V_{IL}	Low-level input voltage				0.8			0.8	٧
Іон	High-level output current				-12			-15	mA
loL	Low-level output current				32			48	mA
fclock*	Clock frequency		0		75	0		90	MHz
. *	Pulse duration	CLKBA or CLKAB high	6			5			ns
t _w *		CLKBA or CLKAB low	7			6			
t _{su} *	Setup time, A before CLKAB↑ or B before	CLKBA [↑]	7			6			ns
t _h *	Hold time, A after CLKAB↑ or B before CLKBA		0			0		·	ns
TA	Operating free-air temperature		-55		125	0		70	°C

^{*} On products compliant to MIL-STD-883, Class B, this parameter is based on characterization data but is not production tested.

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PARAMETER		TEST CONDITIONS		SN	154AS64	l6	SN74AS646			LINUT
		lesico	SI CONDITIONS		TYP	MAX	MIN	TYP	MAX	UNIT
V_{IK}		V _{CC} = 4.5 V,	l _l = −18 mA			-1.2			-1.2	V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -2 \text{ mA}$	V _{CC} -2			V _{CC} -2			
Vau			$I_{OH} = -3 \text{ mA}$	2.4	3.2		2.4	3.2		V
VOH		V _{CC} = 4.5 V	$I_{OH} = -12 \text{ mA}$	2						V
			$I_{OH} = -15 \text{ mA}$				2			
Vai		V _{CC} = 4.5 V	$I_{OL} = 32 \text{ mA}$		0.25	0.5				V
VOL		ACC = 4.2 A	I _{OL} = 48 mA					0.35	0.5	V
l.	Control inputs	$V_{CC} = 5.5 V$,	V _I = 7 V			0.1			0.1	mA
Ξ	A or B ports	$V_{CC} = 5.5 V$,	V _I = 5.5 V			0.1			0.1	ША
I	Control inputs	V FEV	\			20			20	
lіН	A or B ports‡	$V_{CC} = 5.5 \text{ V},$	V _I = '2'.7' V			70			70	μΑ
	Control input) (m) () (-0.5			-0.5	
ΙΙL	A or B ports‡	$V_{CC} = 5.5 \text{ V},$	$V_{ } = 70.4' \text{ V}$			-0.75			-0.75	mA
ΙΟ§		V _{CC} = 5.5 V,	V _O = 2.25 V	-30		-112	-30		-112	mA
			Outputs high		120	195		120	195	mA
Icc		V _{CC} = 5.5 V	Outputs low		130	211		130	211	
			Outputs disabled		130	211		130	211	

 $[\]uparrow$ All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25 \text{ °C}$.

[‡] For I/O ports, the parameters I_{IH} and I_{IL} include the off-state output current.

[§] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

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PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 4.5 V to 5.5 V, C_L = 50 pF, R1 = 500 Ω , R2 = 500 Ω , T_A = MIN to MAX \dagger				UNIT
			SN54AS646		SN74AS646		1
			MIN	MAX	MIN	MAX	
f _{max} *			75		90		MHz
t _{PLH}	CLKBA or CLKAB	A or B	2	9.5	2	8.5	ns
^t PHL		AOID	2	10	2	9	
^t PLH	A or B	B or A	2	11.5	2	9	ns
[†] PHL		DOIA	1	8	1	7	113
[†] PLH	SBA or SAB^‡	A or B	2	13.5	2	11	ns
[†] PHL	SDA OF SAB +	AOID	2	11	2	9	113
^t PZH	o e	A or B	2	11	2	9	ns
[†] PZL	OE .	7 01 0	3	15	3	14	113
^t PHZ	Œ	A or B	2	11	2	9	ns
^t PLZ	OE	AOID	2	11	2	9	115
^t PZH	DIR	A or B	3	21	3	16	ns
t _{PZL}	טוא	7015	3	24	3	18	113
[†] PHZ	DIR	A or B	2	12	2	10	ne
t _{PLZ}	DIK	7016	2	12	2	10	ns

^{*} On products compliant to MIL-STD-883, Class B, this parameter is based on characterization data but is not production tested.

[†] For conditions shown MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡] These parameters are measured with the internal output state of the storage register opposite that of the bus input.

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}	7 N
Input voltage, V _I : Control inputs	7 N
I/O ports	
Operating free-air temperature range, T _A : SN74AS648	0°C to 70°C
Storage temperature range	-65°C to 150°C

recommended operating conditions

			SN74AS648			UNIT
			MIN	NOM	MAX	UNII
Vcc	; Supply voltage			5	5.5	V
V _{IH}	High-level input voltage		2			٧
VIL	Low-level input voltage				0.8	٧
loн	High-level output current				-15	mA
loL	Low-level output current				48	mA
f _{clock}	Clock frequency		0		90	MHz
	Pulse duration	CLKBA or CLKAB high	5	0 9		
t _w	Pulse duration	CLKBA or CLKAB low	6			ns
t _{su}	Setup time, A before CLKAB↑ or B before CLKBA↑		6			ns
th	Hold time, A after CLKAB↑ or B before CLKBA		0			ns
ТА	Operating free-air temperature		0		70	°C

PARAMETER		TEST COND	TEST CONDITIONS		SN74AS648		
		TEST COND	TEST CONDITIONS			MAX	UNIT
VιΚ		V _{CC} = 4.5 V,	I _I = –18 mA			-1.2	٧
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	I _{OH} = -2 mA	V _{CC} -2			
۷он		V _{CC} = 4.5 V	I _{OH} = -3 mA	2.4	3.2		V
			I _{OH} = -15 mA	2			
VOL		$V_{CC} = 4.5 \text{ V},$	I _{OL} = 48 mA		0.35	0.5	٧
	Control inputs	V _{CC} = 5.5 V	V _I = 7 V			0.1	mA
	A or B ports		V _I = 5.5 V			0.1	IIIA
	Control inputs	V _{CC} = 5.5 V,	V _I = 2:7 V			20	4
ΊΗ	A or B ports§					70	μA
	Control input					-0.5	
ll∟	A or B ports§	$V_{CC} = 5.5 V$,	V _I = 70.4 V			-0.75	mA
Io¶		V _{CC} = 5.5 V,	V _O = 2.25 V	-30		-112	mA
			Outputs high		110	185	
Icc		V _{CC} = 5.5 V	Outputs low		120	195	mA
			Outputs disabled		120	195	

[‡] All typical values are at V_{CC} = 5 V, T_A = 25 °C.

The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.



[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

[§] For I/O ports, the parameters I_{IH} and I_{IL} include the off-state output current.

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PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 4.5$ $C_{L} = 50 \text{ pF}$ $R1 = 500 \Omega$ $R2 = 500 \Omega$ $T_{A} = \text{MIN to}$	UNIT			
			SN74/				
f _{max}			90		MHz		
t _{PLH}	CLKBA or CLKAB	A or B	2	8.5	ns		
t _{PHL}		X 61 B	2	9	115		
t _{PLH}	A or B	B or A	2	8	ns		
tPHL	AOFB	D 01 A	1	7	115		
[†] PLH	SBA or SAB ¬‡	A or B	2	11	ns		
[†] PHL	SBA OF SAB +	7 6 6	2	9	113		
^t PZH	Œ	A or B	2	9	ns		
[†] PZL	OE .	7 6	3	15	113		
[†] PHZ	Œ	A or B	2	9	ns		
tPLZ	OE .	7 6 6	2	9	115		
^t PZH	DIR	A or B	3	16	ns		
†PZL	DIR	A OI D	3	18	1115		
tPHZ	DIR	A or B	2	10	ne		
t _{PLZ}	Din	7 01 13	2	10	ns		

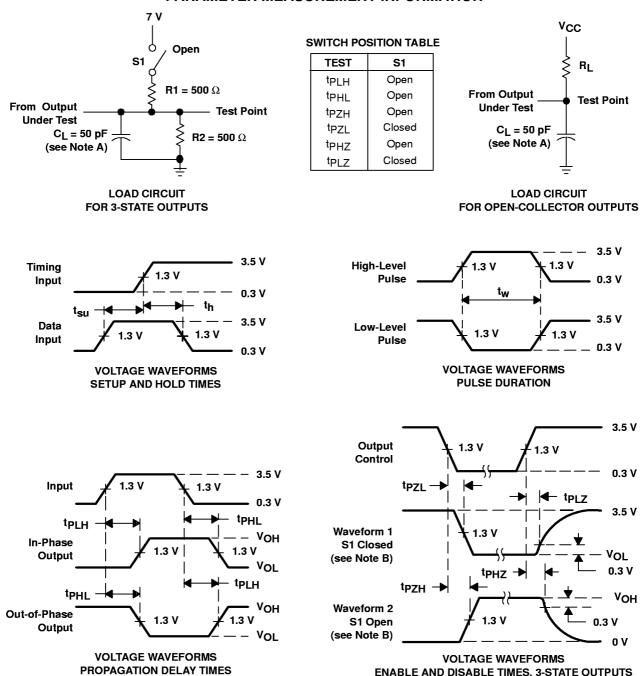
[†] For conditions shown MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡]These parameters are measured with the internal output state of the storage register opposite that of the bus input.

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ENABLE AND DISABLE TIMES, 3-STATE OUTPUTS

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \ \Omega$, $t_f \leq$ 2 ns, $t_f \leq$ 2 ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 2. Load Circuits and Voltage Waveforms



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